

FORM PTO 1449 (modified)			ATTY DOCKET NO. OGOH:108	SERIAL NO. 10/088,264		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT Shin-Itsue TAKEHASHI et al.			
LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>			FILING DATE March 18, 2002	GROUP 2823		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,140,164	10/31/2000	Zhang	438	163	
	6,127,211	10/03/2000	Hirao et al.	438	158	
	5,985,701	11/16/1999	Takei et al.	438	154	
	5,526,304	06/11/1998	Kawamura	365	154	
	5,476,802	12/19/1995	Yamazaki et al.	437	21	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION NO YES
	03-148834	06/25/1991	Japan			Abstract
	5-55248	03/05/1993	Japan			x
	05-082552	04/02/1993	Japan			Abstract
	06-112222	04/22/1994	Japan			Abstract
	7-183403	07/21/1995	Japan			x
	08-032080	02/02/1996	Japan			Abstract
	08-148691	06/07/1996	Japan			Abstract
	9-298304	11/18/1997	Japan			x
	11-163366	06/18/1999	Japan			Abstract
OTHER DOCUMENT(S) <i>Including Author, Title, Date, Pertinent Pages, Etc.</i>						
EXAMINER	<i>Milena D. I. Ol</i>			DATE CONSIDERED 3/10/04		

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>BAE</i>	<i>JUL 08 2002</i>					
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION NO YES
	11-168221	06/22/1999	Japan			x
	9-148266	06/06/1997	Japan			x
	10-233511	09/02/1998	Japan			Abstract
OTHER DOCUMENT(S) <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>						
	"Laser Crystallised Poly-Si Circuits for AMLCDs" Edwards, M.J., et al. ASIA DISPLAY '95, pp. 335-337.					
	"New Poly-Si TFT Structure for OFF-Current Reduction" Bae, B.S., et al. SID '96 DIGEST, pp. 25-28.					
	"AMLCDs and Electronics on Polymer Substrates" Young, N.D., et al. Euro Display '96, pp. 555-558.					
	"Gate-Overlapped Lightly Doped Drain Poly-Si Thin-Film Transistors for Large Area-AMLCD" Choi, Kwon-Young, et al. IEEE Transaction on Electronic Devices, Vol. 45, No. 6, June 1998, pp. 1272-1279.					
EXAMINER <i>MILLER</i>	DATE CONSIDERED <i>3/10/04</i>					

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